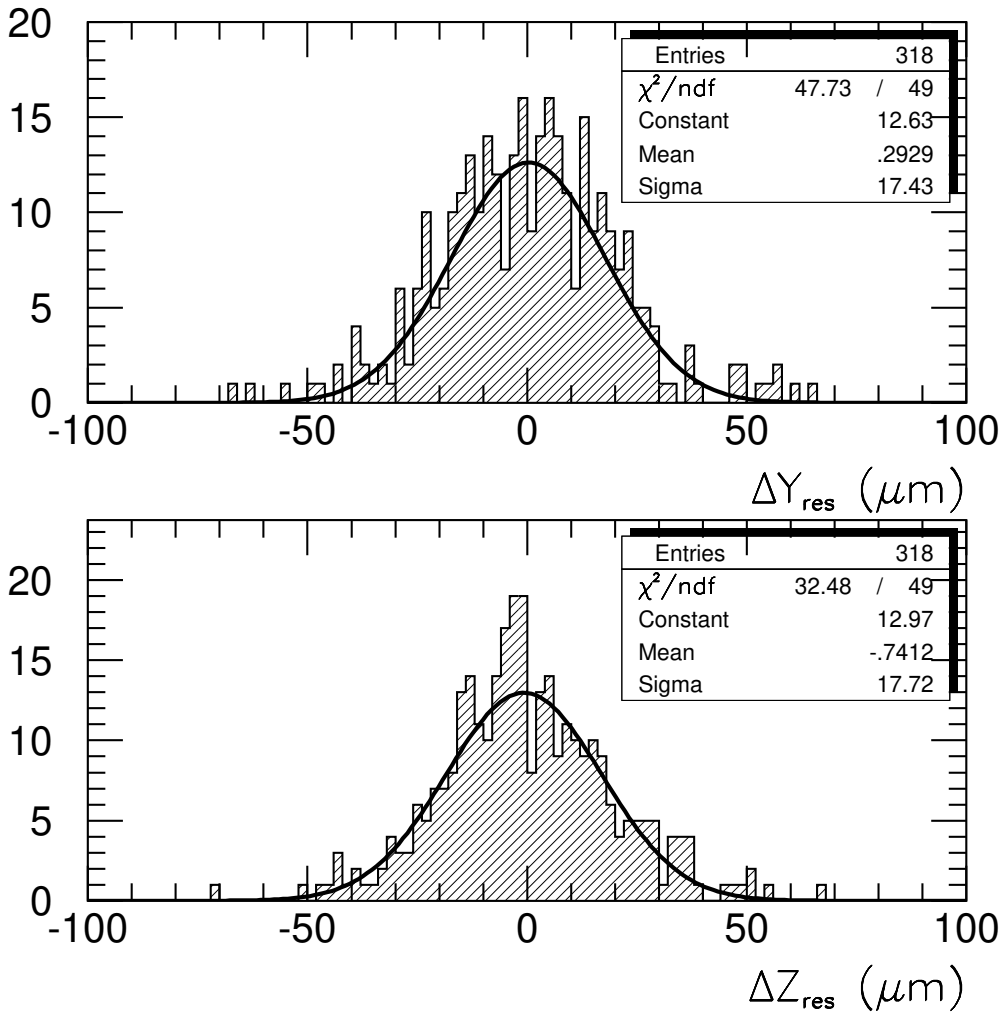
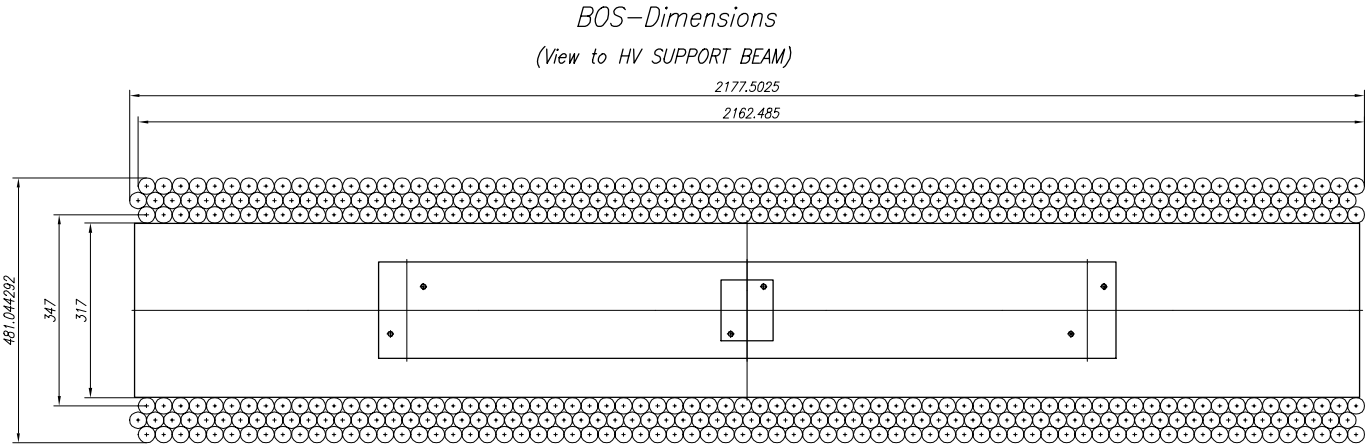
X-Ray Measurement of MDT Chamber



Residuals of wire pos. w.r.t. ideal grid: accuracy

< 18 μm rms



Parameter [μm]	Design value	X-ray meas.
Horiz. wire pitch	30036.8 ± 0.6	30036.2 ± 0.1
Vertical wire pitch	26054 ± 10	26060 ± 1.0
Horiz. layer shift	0 ± 10	3 ± 16
Vertical layer shift	0 ± 10	6 ± 12

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